

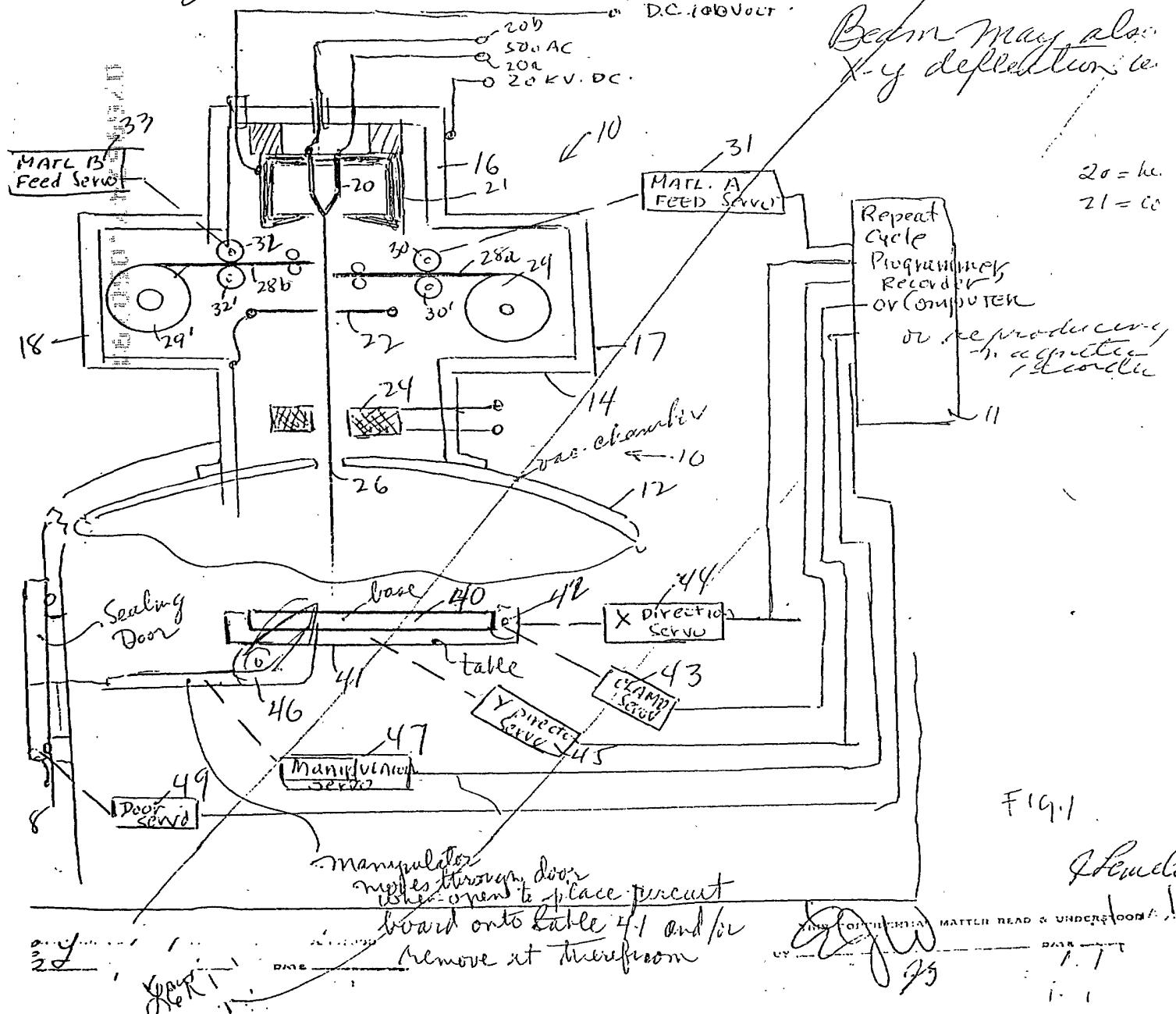
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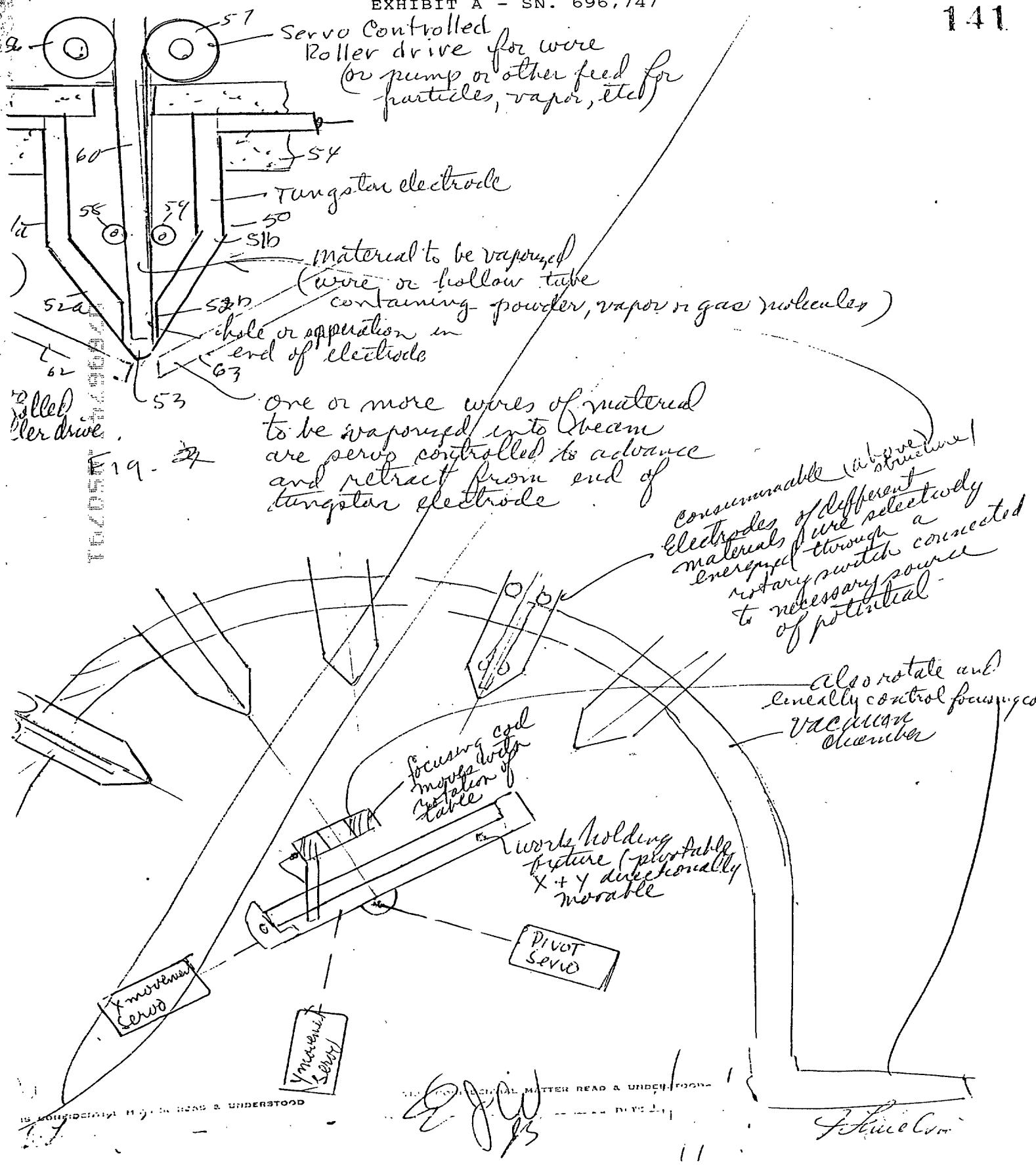
written and recorded (number),  
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# Electron Beam Deposition of Circuits

The following arrangements have been conceived for i.e. depositing electronic circuits onto bases:





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In the electron beam apparatus of pp 140\*141  
 the claims for which I have been working on over  
 past 10 months it is noted that -

(1) The beam may be deflection controlled  
 by means of an analog signal or signals  
 using deflection plates of conventional design

(2) The beam focus

All servos such as door to vac. chamber  
 opening & closing servo, work positioning servo  
 & servos for feeding materials into the beam  
 manipulators for admitting and removing work  
 from chamber, work clamping servo, etc. as well  
 as the means for controlling focus, deflection, etc  
 and selection of (one of a multitude of) beam may be  
 automatically controlled on a timer cycle  
 of operation by means of a programming mean  
 such as a magnetic or other recorder on which  
 is recorded the necessary analog and/or digital  
 signals to effect feed control which record  
 is operated and transduced from the above said  
 signals in a predetermined sequence -

(3) Material to be deposited may be added  
 to beam as a rod or wire, powdered, liquid, vi  
 gas which materials are carried along by  
 beam to work piece and focused thereon by  
 Beam energy or modulation may be controlled  
 by a reproducible analog or digital signals to  
 prepare (heat or erode, melt or vaporize) surface  
 base on which selected deposits are to  
 be made

(4). Chemical reactions  
 may take place in beam alloying, doping, etc  
 beam and material therein by means of  
 inter-surface intersected by beam

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BY

J. J. J.

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machining or otherwise physically  
chemically changing material deposited  
can only be effected by change of  
beam energy, etc or by means of  
more auxiliary beams (generated  
same gun or chamber of different guns)  
are similarly deflection controlled and

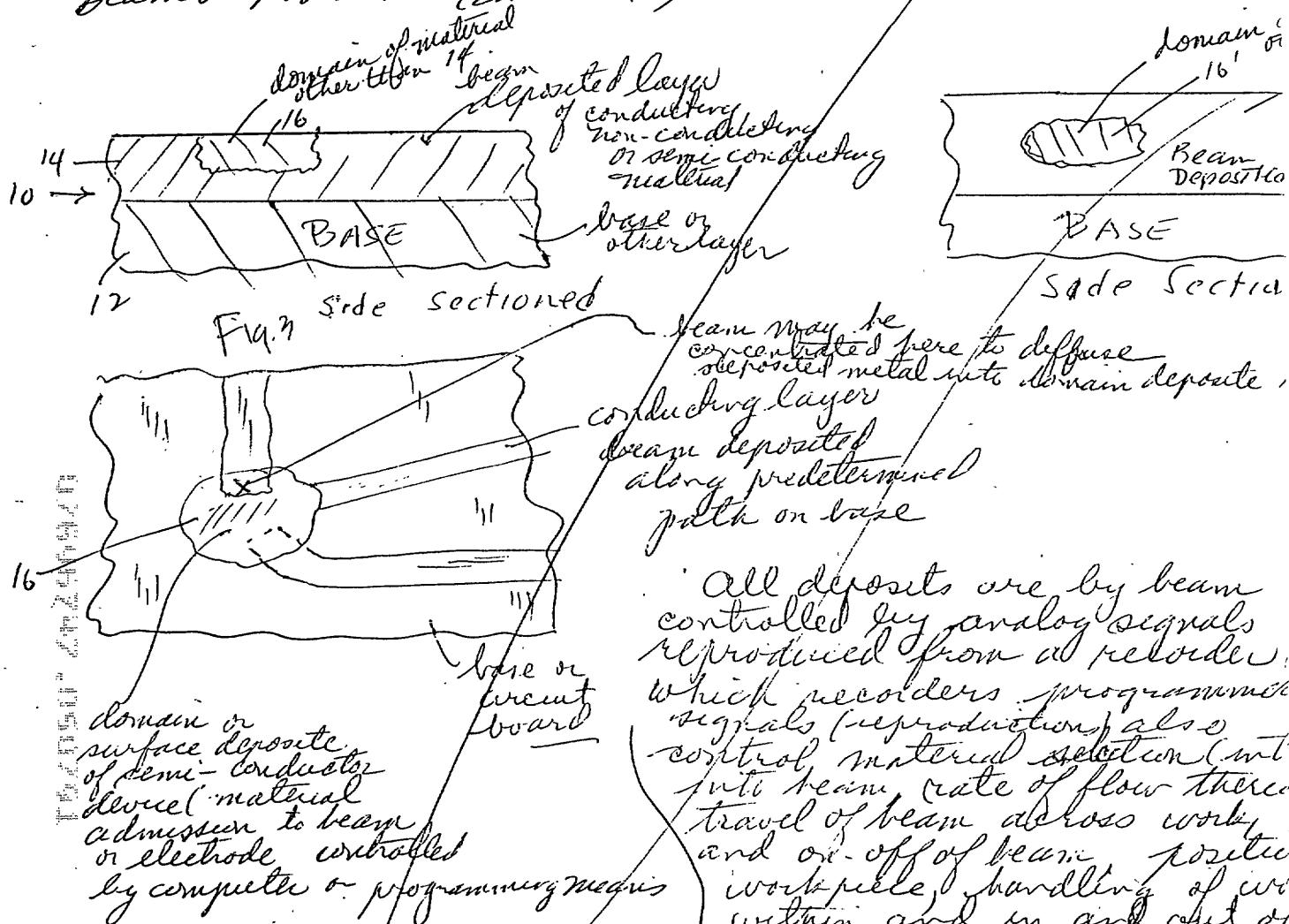
material to be deposited (wire, powder, vapor,  
gas) may be positionally controlled by  
servos controlled by the programming  
controlling the other variable to be  
placed or moved into the volume  
focus of the beam directly above surface

or may be focused in gun into which  
material is selectively fed and controlled  
by programming means. After focus beam  
is diverged or directed as a narrow  
beam against surface of work and/or deflectionally

auxiliary beam may feed into main beam  
after or at its focus or near its generation  
which auxiliary beams contain atoms of  
material to be deposited onto surface by  
beam which may be deflection controlled  
after in accordance with a programmed

optical maser may be used as an  
auxiliary beam generator in conjunction with  
arrangements or in place of electron  
generating means thereof. Maser beam  
is travelled inside or parallel to electron beam  
is, or may be directed at the focus  
electron beam to cooperate in machining  
remove a portion of surface of work or evaporatively  
used to be fed to beam.

## Beam Deposition (Continued) 15



Feedback signals for indicating how much material is deposited and where to control beam position, flow and selection of different materials to be admitted to beam may be effected by means of a reading electron beam directed by computer or programmed (recorded signals) to scan selected area or scanning entire target as material is deposited or during periods when material

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is being deposited (inspection scanning period). The hot video signal derived by beam scanning is to be analyzed by techniques as described in pending application "Automatic Inspection System" digitally determining in digital form the characteristics (optical characteristics) of the material deposited.

Spectroscopy may also be employed in which a beam is directed against the beam in a and causes an emission of electrons therefrom which is spectrally analyzed, the results of which are used to control further deposition or removal of deposited material.

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Conrad J. Waldrep 11/11/11  
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### Classification of Electron Beam Deposition Apparatus & Methods

The following are arrangements, apparatus and methods I have conceived relating to electron beam manufacture of micro-circuits which I intend to incorporate in a number of my applications.

Deflection and intensity control of deposition (or machining, welding, electron beam or beams attained by one of the following techniques):

- Reproduced magnetically recorded video picture signal or signals.
- video signal generated by scanning optical recording
- output of digital recorder
- output of comparator (summing amplifier) fed (a), or (b) above plus feedback signal generated by scanning either or both beams containing deposition material or surface containing deposited material.

Correction for over or incorrect area deposition may be made controlling beam per-area (by computer command signals or input of summing amplifier being fed command reproduced video signal and feedback scanning signal) which beam either

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machines or vaporous material already deposited, \* \* \*  
 \* \* Vapored material (vapored by corrective beam) may be removed from surface of workpiece by another beam or deflection controlled or otherwise positioned to effect such removal.

Correction for over deposition may also be made - deflection controlled beam containing an oxidizing or other compound.

Work may be positionally controlled by command signals derived from command recording as described or by receiving command and feedback signals as described.

**I** Deflection control of beam (x, y. position plus intensity modulation plus position of focus) & control depending on position of the surface being beam-deposited on.

- depositing semi-conductors, metal or dielectric material
- depositing plural materials simultaneously different
- " " simultaneously different
- introducing different materials at different times by different single heater
- welding, machining, vaporizing deposited material

**II** Feed back signal compared with reference command (representing beam control signal) is generated by:

- beam scanning and analysis of ionized or vaporized parts therein as beam is generated and materials admitted there
- optical beam or work scan plus analysis
- spectroscopy or spectrographic (automatic) analysis - mass spectrograph + scan
- electron beam scan of deposited work with a video read beam

**IV** Material feed (to beam) by and as:

- rod or wire, servo driven into beam, into beam focus, into electrode generating beam (into voltage between electrodes) or directly into beam at work. Servo controlled by direct command or command or output receiving reproduced command signal plus feed back signal.
- servo controlled powder feed (as above)
- servo valve controlled (as above) feed of liquid conta

ition material into beam (or vapourized deposition material into beam).

### Plural Beams

Plural reproduced deflection control signals plus beam control or reference signals, plus work positioning also (optional), plus focus adjustment signals (optional) others mentioned above are used to simultaneously sequentially control beams each depositing different material alternately.

### Beam Deposition Techniques (Miscellaneous features)

- (a) Electron beam plus photographic techniques.
  - (i) Beam deposits components onto conducting film pattern formed by photo-etching, photo-composition (exposure to light and developing)
  - (2) Optical beam (laser light beam) is deflection controlled and cooperates with deflection controlled electron beam in welding, machining, effecting deposition, chemically reacting (on dep. materials) deposited by electron beam, etc. Laser light beam may also be used to carve photoresist film, expose it over all, develop image, used for corrective purposes (vapourize or machine material) (film) deposited by electron beam, vapourize material(s) to be deposited or directed by electron beam, etc. work, etc. Laser beam deflection controlled by servo controlled mirror(s) controlled by reproduced command signal or output of comparator or computer
- (b) Plural beams cooperate. One vaporizes (laser or electron beam) material to be deposited, feeds it at or to second deposition beam which is deflection controlled and deposits material, and beam scans either second beam or surface which is just received material to provide a feedback signal to a comparator (summing amplifier or other) which provides an output to control both first and second beams (i.e. on-off or intensity or focus of first beam and position of second beam) (first and second beams controlled by respective command signals fed to

Well by passing beam through mask

respective comparator means each of which receives some feedback signal generated by said beam scanning what is being or was just deposited

(c) An apparatus for repairing, modifying or adding micro-structure circuitry has also been conceived based on beam scanning the circuit already deposited (surface scanning) and determining by reading with the beam the physical-optical or atomic structure of the circuit, by x-ray scanning, by opt. scanning said circuit (with a modulated light beam) or by a combination of two or three of these scanning techniques, been conceived. The output signal derived by scanning is fed to a computer, which thereafter provides signals for controlling beam deflection, modulation, position of workpiece, material selection and feed to beam, mask selection, etc to effect a desired repair, change in structure, etc.

(d) Vaporization of material in a primary electron beam by means of a mesh through which beam(s) are deposited beam is passed and picks up the material to be deposited, carried material changed by, new composition(s) formed in a beam directed against a workpiece by either the action of the beam per se or the reaction of the beam (temperature, etc) and two or more of the materials admitted thereto or one or more admitted material and material of the workpiece.

(f) Growth of predetermined crystal structure by means of melting material(s) admitted thereto and deposited, or by a combination of materials admitted to beam being deposited thereby onto a crystal being grown. Programmed control of beam deflection, on-off-modulation, focus; crystal movement, material flow into beam (based on feedback derived by said beam, crystal, etc. (as described above) fed into comparator also command signal and providing difference signal for control.

(g) Creation of mask through which erosion electron beam is directed for chemically or mechanically affecting (or changing chemically, welding, etc) the workpiece by means of photosensitive mask material, thermoplastic according to film of General Electric Co. which mask is formed by exposure to a write beam of said mask material which writing beam is mod. to affect the desired image (transparent and opaque or rep. pattern in the mask). Mask may be in the field of the

ted against the workpiece (in path of beam)

(b) Use of a unique mask in beam path made of a grating - as a diffraction grating, produced by beam etching thin plate, selective and controlled deposition of material introduced in beam, or to or after passing thru mask. Plural diffraction gratings used at right angles to each other will produce line beams < than .001 inches in diameter.

(c) Use of a mask to break up beam intense electron or mass beam into a plurality of beams directed thereafter against selected areas of the workpiece for the effecting welding, brazing (hole drilling), erosion or deposition onto said select

(d) Program control (plus feedback where necessary) of beam current (deflection), focus, etc. of position of workpiece, and different materials feed into beam to selectively deposit different materials onto different areas of workpiece

(e) Exposure, machining, chemically changing, development and baking of a photoresistive material to form a circuit by means of beam and use of beam to deposit semi-conducting, dielectric, insulating materials onto selected areas of photoresistively developed circuit <sup>all by automatic control as above</sup>

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**PAGE 150 - IS MISSING**

Extrude multiple sheets or strips apart, & filaments of different materials) & laminate continuously.

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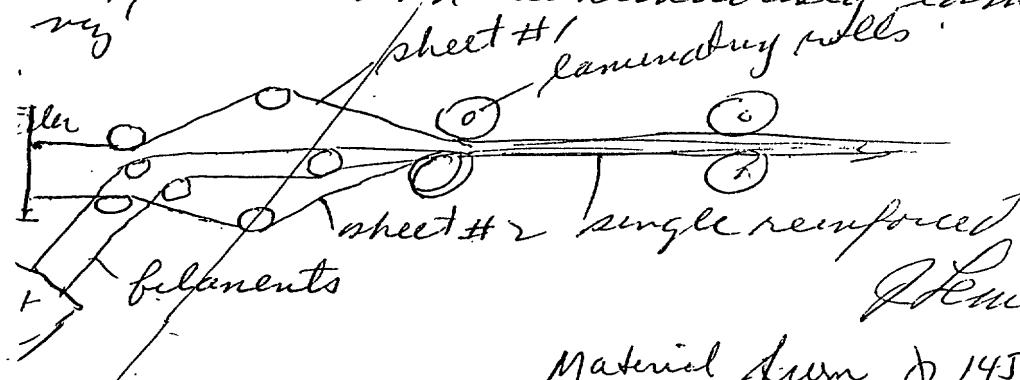
To rods, tubes, wires or other structural members made of plastic filaments or metal whiskers (single crystals of metal of exceptional strength) which are compacted together and bonded or welded where they cross. They may be encapsulated in another plastic, metal, ceramic, powdered metal, etc to form solid, filament reinforced structures.

It is conceived to simultaneously extrude a plurality of sheets of thermoplastic or ribbons thereof from a single die bar from spaced-apart slit openings and guide said sheets or strips as follows:

(a) First guide apart, continuously, to admit filaments (reinforcing or decorative) or cloth, threads or other material as a continuous or broken web between two of said strips and continuously laminate into a single, integral sheet of reinforced material.

(b) Drive each sheet thru polishing rolls and then laminate (improved clarity).

(c) Simultaneously extrude from another extrusion chamber, a plurality of reinforcing filaments (of glass, polypropylene or other plastic), guide these between at least two of the strips, or ribbons or sheets not extruded and continuously laminate together.



Material from p 145 to this point  
read & understood by me this 4th  
day of [unclear] of Berlin

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